D2661, APRIL 1982-REVISED MARCH 1988

- Fully Buffered to Offer Maximum Isolation from External Disturbance
- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset and clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

The SN54LS112A and SN54S112 are characterized for operation over the full military temperature range of ~55 °C to 125 °C. The SN74LS112A and SN74S112A are characterized for operation from 0 °C to 70 °C.

FUNCTION TABLE (each flip-flop)

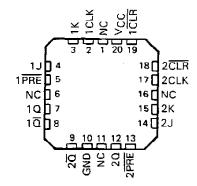
	IN	PUTS			OUTPUTS		
PRE	CLR	CLK	J	K	a	₫	
L	Н	ХХ		Х	Н	L	
н	L	×	Х	X	L	Н	
L	L	×	х	Х	Н [†]	H [†]	
н	Н	1	L	L	ΩO	ᾱo	
H	Н	1	Н	L	Н	L	
Н	H	1	L	н	L	н	
Н	Н	1	Н	н	TOGGLE		
H	_ H	Н	_ х	х	αo	₫o	

[†] The output levels in this configuration are not guaranteed to meet the minimum levels for VOH if the lows at preset and clear are near VIL minimum. Furthermore, this configuration is nonstable; that is, it will not persist when either preset or clear returns to its inactive (high) level.

SN54LS112A, SN54S112 . . . J OR W PACKAGE SN74LS112A, SN74S112A . . . D OR N PACKAGE (TOP VIEW)

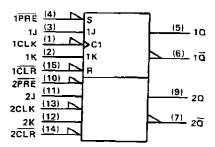
_	_		
1CLK[]1	\cup_{16}	□vcc
1K []2	15	1 CLR
1J[]3	14	2CLR
1PRE]4	13	2CLK
10[]5	12	<u></u> 2κ
10[]6	11	2J
20 [7	10	2PRE
GND [8	9	20

SN54LS112A, SN54S112...FK PACKAGE (TOP VIEW)



NC-No internal connection

logic symbol‡

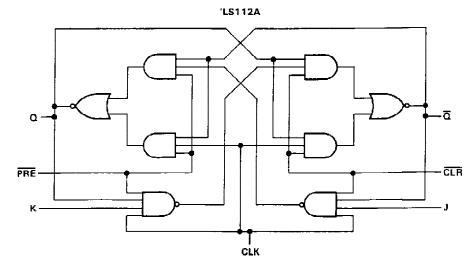


[‡]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

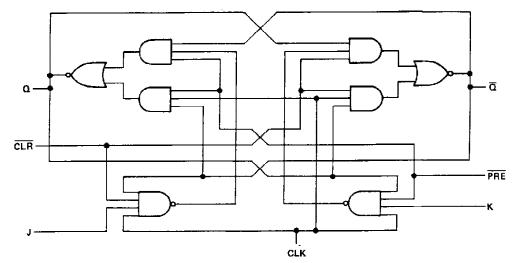
Pin numbers shown are for D, J, N, and W packages.

SN54LS112A, SN54S112, SN74LS112A, SN74S112A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

logic diagrams (positive logic)

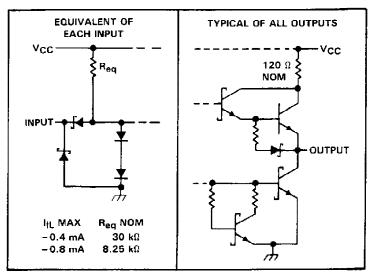


SN54S112, SN74LS112A

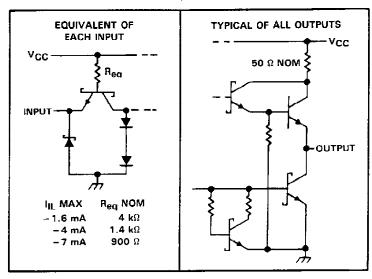


schematics of inputs and outputs

'LS112A



SN54S112, SN74S112A



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	
Input voltage: 'LS112A	<i>.</i>
SN54LS112, SN74LS	112A
Operating free-air temperature range:	\$N54'55°C to 125°C
	\$N74'
Storage temperature range	

NOTE 1: Voltage values are with respect to network ground terminal.

SN54LS112A, SN74LS112A DUAL J-K NEGATIVE-EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

			SN	154LS11	2A	SN	74LS11	2A	LIBUT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
ViH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			8.0	٧
Юн	High-level output current				-0.4		·	-0.4	mА
OL	Low-level output current				4			8	mA
fclock	Clock frequency		0		30	0		30	MHz
	Pulse duration	CLK high	20			20			De.
t _W	roise duration	PRE or CLR low	25	-		25			ns.
		Data high or low	20			20		_ "	
t _{su}	Set up time-before CLK1	CLR inactive	25			25			ns
		PRE inactive	20			20			
th	Hold time-data after CLK1		0			0			пş
Тд	Operating free-air temperature		- 55		125	0		70	°С

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITIONS†		SI	154LS11	2A	SI	174LS11	2A	UNIT
Ρ,	AKAMETER	IEST	CONDITIONS		MIN	TYP!	MAX	MIN	TYP‡	MAX	UNII
v_{iK}		V _{CC} = MIN,	I _I = -18 mA				-1.5			1.5	V
Vон		V _{CC} = MIN, I _{OH} = -0.4 mA	$V_{IH} = 2 V$,	V _{IL} ≠ MAX,	2.5	3.4		2.7	3.4		V
1.0		V _{CC} = MIN, I _{OL} = 4 mA	V _{IL} = MAX,	V _{IH} = 2 V,		0.25	0.4		0.25	0.4	V
VOL		V _{CC} = MIN, I _{OL} = 8 mA	$V_{IL} = MAX$, $V_{IH} = 2 V$,						0.35	0.5	
	J or K						0.1			0.1	
Ιį	CLR or PRE	V _{CC} = MAX,	V _I = 7 V				0.3			0.3	mA
	CLK	1			-		0.4			0.4	
	J or K		·				20			20	
ΉΗ	CLR or PRE	V _{CC} = MAX,	$V_{\parallel} = 2.7 \ V$		-		60	_		60	μА
	CLK	1					80			80	
1	JorK	V _{CC} = MAX,	V. = 0.4 V				-0.4			-0.4	mA
ll .	All other	ACC - IAIWY	V1 = 0.4 V				-0.8			-0.8	
los [§]		VCC = MAX,	see Note 2		- 20		- 100	- 20		- 100	mA
ICC (T	otal)	V _{CC} = MAX,	see Note 3			4	6		4	6	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

 $^{^{\}ddagger}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_{A} = 25 \,^{\circ}\text{C}$.

Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

NOTES: 2. For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with $V_0 = 2.25 \text{ V}$ and 2.125 V for the '54 family and the '74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.

^{3.} With all outputs open, ICC is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, V_{CC} = 5 V, T_A = 25 °C (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
f _{max}			-	30	45		MHz
tPLH	CLR. PRE or CLK	٥ ٦	$R_L = 2 k\Omega$, $C_L = 15 pF$		15	20	กร
†PHL	CLM, PRE OF CLK	Q or Q		[15	20	пs

NOTE 4: Load circuits and voltage waveforms are shown in Section 1.

SN54S112, SN74S112A DUAL J-K NEGATIVE EDGE-TRIGGERED FLIP-FLOPS WITH PRESET AND CLEAR

recommended operating conditions

			SN54S112			SI	174511	2A	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	4.75	5	5.25	٧
ViH	High-level input voltage	2			2			V	
VIL	Low-level input voltage			•	0.8			0.8	٧
ЮН	High-level output current				- 1			- 1	mΑ
loL	Low-level output current				20	Ī		20	mΑ
		CLK high	6			6		.,,	
tw	Pulse duration	CLK low	6.5		-	6.5			пѕ
		PRE or CLR low	8			8			
t _{SU}	Set up time-before CLK1	Data high or low	7			7			กร
th	Hold time-data after CLK↓		0			0			ns
TA	Operating free-air temperature		-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		TEST CONDITIONS†			S	N54S1	12	SI	N74S11:	2A	LIBUT
PA	RAMETER	IESI	CONDITIONS		MIN	TYP [‡]	MAX	MIN	TYP‡	MAX	UNIT
VIK		V _{CC} = MIN.	lj = -18 mA	***		-	-1.2			-1.2	٧
VoH		V _{CC} = MIN, I _{OH} = -1 mA	V _{IH} = 2 V,	VIL = MAX,	2.5	3.4		2.7	3.4		٧
VOL		V _{CC} = MIN, I _{OL} = 20 mA	V _{IH} = 2 V,	V _{IL} = 0.8 V,			0.5			0.5	٧
Iį			V ₁ = 5.5 V				1			1	mA
	J or K	VCC = MAX.	V - 2.7 V				50			50	μА
łН	All other	T VCC = MAX.	V = 2.7 V				100			100	μΑ
	J or K						- 1.6			-1.6	
	CLR [§]],,	V 05V				-7			-7	mΑ
ΙΙΓ	PRE 5	V _{CC} = MAX,	V; = 0.5 V	$V_{\parallel} = 0.5 \text{ V}$		•	-7			-7	MA
	CLK	1					-4			- 4	
los¶		V _{CC} = MAX			-40		- 100	-40		~ 100	mA
CC#		V _{CC} = MAX,	see Note 3			15	25		15	25	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

 $^{^{\}ddagger}$ All typical values are at V_{CC} = 5 V, T_A = 25 °C.

[§]Clear is tested with preset high and preset is tested with clear high.

Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

[#]Values are average per flip-flop.

NOTE 3: With all outputs open, I_{CC} is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

switching characteristics, VCC = 5 V, TA = 25 °C (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
fmax				80	125		MHz
tPLH	PRE or CLR	Q or Q			4	7	ns
4	PRE or CLR (CLK high)	Ō or O	B. 200.0 0. 455		5	7	
†PHL	PRE or CLR (CLK low)	u or u	$R_L = 280 \Omega$, $C_L = 15 pF$		5	7	ns
^t PLH	CLK	Q or $\overline{\mathbf{Q}}$			4	7	nŝ
tPHL .	CER	Q 01 Q	<u> </u>		5	7	ns

NOTE 4: Load circuits and voltage waveforms are shown in Section 1.

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SN54LS112A, Dual J-K Negative-Edge-Triggered Flip-Flops With Preset And Clear Device Status: Active

- > Description
- > Features
- > Datasheets
- > Pricing/Samples/Availability
- > Application Notes
- > Related Documents
- > Training

Parameter Name	SN54LS112A				
Voltage Nodes (V)	5				
Vcc range (V)	4.5 to 5.5				
Input Level	TTL				
Output Level	TTL				
Output	2S				
No. of Bits	2				

Description

These devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset and clear inputs sets or resets the outputs regardless of the levels of the other inputs. When preset and clear are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by tying J and K high.

The SN54LS112A and SN54S112 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74LS112A and SN74S112A are characterized for operation from 0°C to 70°C.

Features

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- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

To view the following documents, Acrobat Reader 3.x is required.

To download a document to your hard drive, right-click on the link and choose 'Save'.

Datasheets

Full datasheet in Acrobat PDF: sdls011.pdf (300 KB)

Full datasheet in Zipped PostScript: sdls011.psz (328 KB)

Pricing/Samples/Availability

Orderable Device	Package	Pins	Temp (°C)	Status	Price/unit USD (100-999)	Pack Qty	DSCC Number	Availability / Samples
JM38510/30103B2A	<u>FK</u>	20	-55 TO 125	ACTIVE	8.27	1		Check stock or order
JM38510/30103BEA	J	16	-55 TO 125	ACTIVE	2.92	1		Check stock or order
JM38510/30103BFA	W	16	-55 TO 125	ACTIVE	7.75	1		Check stock or order
SN54LS112AJ	J	16	-55 TO 125	ACTIVE	0.70	1		Check stock or order
SNJ54LS112AFK	<u>FK</u>	20	-55 TO 125	ACTIVE	7.75	1		Check stock or order
SNJ54LS112AJ	J	16	-55 TO 125	ACTIVE	1.42	1		Check stock or order
SNJ54LS112AW	W	16	-55 TO 125	ACTIVE	8.77	1		Check stock or order

Application Reports

View Application Reports for Digital Logic

- <u>Designing With Logic</u> (SDYA009C Updated: 06/01/1997)
- Designing with the SN54/74LS123 (SDLA006A Updated: 03/01/1997)
- Input And Output Characteristics Of Digital Integrated Circuits (SDYA010 Updated: 10/01/1996)
- <u>Live Insertion</u> (SDYA012 Updated: 10/01/1996)

Related Documents

- Documentation Rules (SAP) And Ordering Information (SZZU001B, 4 KB Updated: 05/06/1999)
- Logic Selection Guide Second Half 2000 (SDYU001N, 5035 KB Updated: 04/17/2000)
- MicroStar Junior BGA Design Summary (SCET004, 284 KB Updated: 07/28/2000)
- More Power In Less Space Technical Article (SCAU001A, 850 KB Updated: 03/01/1996)

Product Folder:SN54LS112A, Dual J-K Negative-Edge-Triggered Flip-Flops With Preset And Clear

Table Data Updated on: 9/7/2000

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